

# **Enhancement Mode N-Channel Power MOSFET**

TSSOP8/NMOS/20V/ $\pm$ 12V/0.8V/5A/24m $\Omega$  Rev0.5





# 20V, $24m\Omega$ , 5A, N-Channel Enhancement Mode Power MOSFET

#### 1.Features

- High Power and current handing capability
- Lead free product is acquired
- Surface Mount Package

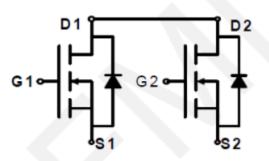
V <sub>DS</sub> Typ	RDS(on) Typ.	I⊳ Max.	
20V	24mΩ @ 4.5V	5A	
200	34mΩ @ 2.5V	<i>5</i> A	

### 2.Applications

- Battery protection
- Load Switch
- Power management



Pin Description



Schematic Diagram

## 3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Tube	PCS/CTN.
WP8205KT8	<u>8205A</u>	TSSOP8	5,000	80,000

#### 4. Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	Voss	20	V
Gate to Source Voltage	Vgss	±12	V
Drain Current- Continuous	lσ	5	Α
Drain Current (Pulse)	Ідм	20	Α
Maximum Power Dissipation	Po	1.7	W
Operating Junction and Storage Temperature Range	Tj, Tstg	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### 5.Thermal Characteristic

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction to Ambient (Note 2)	Reja	75	°C/W

Note 2: When mounted on 1 inch square copper board  $t \le 10 sec$  The value in any given application depends on the user's specific board design.



# 6.Electrical Characteristics at Ta=25°C (Note 3)

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V(BR)DSS	I <sub>D</sub> = 250µA, V <sub>GS</sub> = 0V	20			V
Zero-Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V			1	μΑ
Gate-Body Leakage Current	Igss	V <sub>GS</sub> = ±12V, V <sub>DS</sub> = 0V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250µA	0.5	0.8	1.0	V
Drain to Source On-State	Rps(an)	I <sub>D</sub> = 5A, V <sub>GS</sub> = 4.5V		24	30	mΩ
Resistance	RDS(on)	I <sub>D</sub> = 2A, V <sub>GS</sub> = 2.5V		34	45	mΩ
Diode Forward Voltage	Vsp	Is = 5A, V <sub>GS</sub> = 0			1.0	V
Input Capacitance	Ciss	V <sub>GS</sub> =0V,		455		pF
Output Capacitance	Coss	V <sub>DS</sub> =10V,		64		pF
Reverse Transfer Capacitance	Crss	Frequency=1.0MHz		55		pF
Turn-ON Delay Time	<b>t</b> d(on)	V <sub>DS</sub> = 10V,		4		ns
Turn-ON Rise Time	tr	$V_{GS} = 10V,$ $V_{GS} = 4.5V,$		10		ns
Turn-OFF Delay Time	t <sub>d(off)</sub>	$R_{GEN} = 3\Omega$ ,		65		ns
Turn-ON Fall Time	tf	I <sub>D</sub> =2A		33		ns
Total Gate Charge	Qg	V <sub>DS</sub> = 10V,		6		nC
Gate- Source Charge	Qgs	V <sub>GS</sub> =0 to 4.5V,		1		nC
Gate- Drain Charge	Qgd	I <sub>D</sub> = 2A		1.5		nC

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



# 7. Typical electrical and thermal characteristics

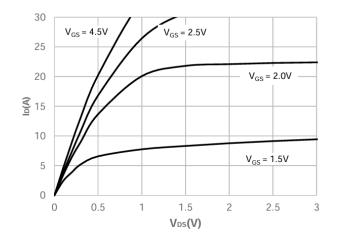
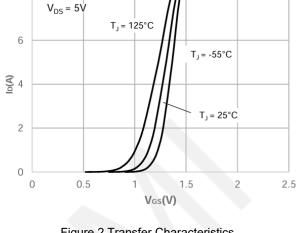


Figure 1 On-Region Characteristics



8

Figure 2 Transfer Characteristics

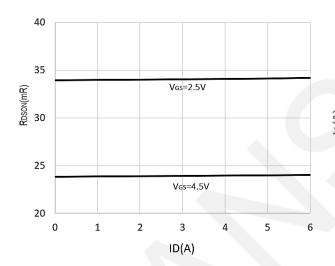


Figure 3 On-Resistance vs. Drain Current and Gate Voltage

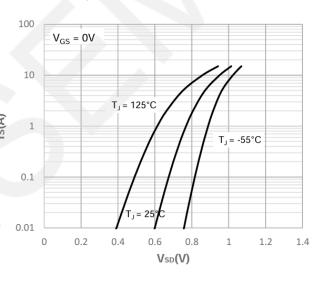


Figure 4 Body Diode Characteristics

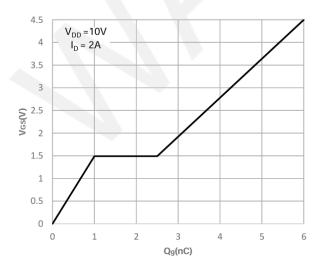


Figure 5 Gate Charge Characteristics

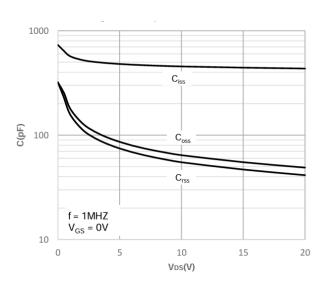
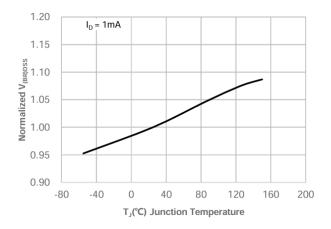


Figure 6 Capacitance Characteristics



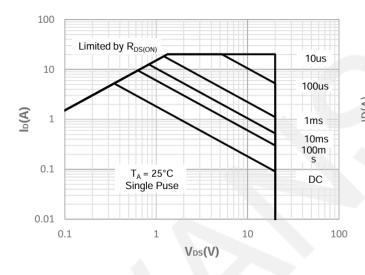


2.2  $V_{GS} = 4.5V$   $I_D = 6A$ 2 1.8 Normalized R<sub>DS(ON)</sub> 1.6 1.4 1.2 1 0.8 0.6 0.4 -80 -40 40 80 120 160 200 T<sub>J</sub>(°C) Junction Temperature

Figure 7 Normalized Breakdown voltage vs. Junction Temperature

Figure 8 Normalized on Resistance vs.

Junction Temperature



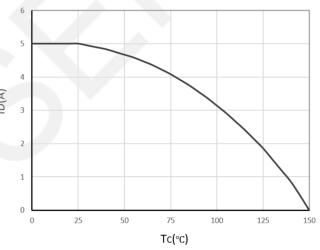


Figure 9 Maximum Forward Biased Safe Operating Area

Figure 10 Maximum Continuous Drian Current vs.

Ambient Temperature

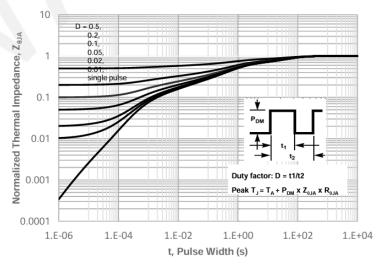
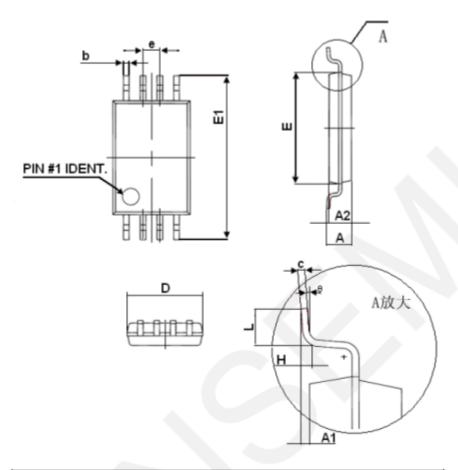


Figure 1 1 Normalized Maximum Transient Thermal Impedance WAN SEMICONDUCTOR (NINGBO) CO.,LTD



# 8.Package Dimensions



Cumbal	Dimensions	In Millimeters	
Symbol	Min	Max	
D	2.900	3.100	
E	4.300	4.500	
b	0.190	0.300	
С	0.090	0.200	
E1	6.250	6.550	
Α		1.100	
A2	0.800	1.000	
A1	0.020	0.150	
е	0.65(BSC)		
L	0.500	0.700	
Н	0.25(TYP)		
0	1° 7°		



#### 9.Important Notice

WAN SEMICONDUCTOR (NINGBO) CO., LTD reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services and to discontinue any product or service. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to WANSEMI's terms and conditions of sale supplied at the time of order acknowledgment.

WANSEMI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in WANSEMI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent WANSEMI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

WANSEMI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using WANSEMI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

No WANSEMI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Unless WANSEMI has specifically designated certain components which meet ISO/TS16949 requirements, mainly for automotive use, WANSEMI will not be responsible for any failure of such components to meet such requirements.